

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	497	349/40	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/25 15:06
L2	2	1 and short\$3 adj2 (bar wir \$3 line circuit) with flexible adj2 circuit	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/25 15:09
L3	20	1 and (short\$3 test\$3 inspect \$3) adj2 (bar wir\$3 line circuit) and flexible adj2 circuit and (ic integrated adj circuit)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/25 15:16
L4	527	349/54	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/25 15:23
L5	17	4 and (short\$3 test\$3 inspect \$3) adj2 (bar wir\$3 line circuit) and flexible adj2 circuit and (ic integrated adj circuit)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/25 15:23
L6	396	349/192	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/25 15:32

L7	14	6 and (short\$3 test\$3 inspect \$3) adj2 (bar wir\$3 line circuit) and flexible adj2 circuit and (ic integrated adj circuit)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/25 15:32
L8	1512	349/149	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/25 15:50
L9	66	8 and (short\$3 test\$3 inspect \$3) adj2 (bar wir\$3 line circuit) and flexible adj2 circuit and (ic integrated adj circuit)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/25 15:51
L10	617	349/150	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/25 15:51
L11	28	10 and (short \$3 test\$3 inspect\$3) adj2 (bar wir \$3 line circuit) and flexible adj2 circuit and (ic integrated adj circuit)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/25 15:51
L12	689	349/151	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/25 15:52

L13	30	12 and (short \$3 test\$3 inspect\$3) adj2 (bar wir \$3 line circuit) and flexible adj2 circuit and (ic integrated adj circuit)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/25 15:52
L14	856	349/152	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/25 15:52
L15	32	14 and (short \$3 test\$3 inspect\$3) adj2 (bar wir \$3 line circuit) and flexible adj2 circuit and (ic integrated adj circuit)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/25 15:52
L16	2	((liquid adj crystal lcd) and (short\$3 test\$3 inspect \$3) adj2 (bar wir\$3 line circuit) and flexible adj2 circuit and (ic integrated adj circuit) and (test\$3 inspect \$3 bound\$3 short\$3) adj2 (pad terminal)). clm.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/25 15:57
L17	7259	345/87	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/25 15:59

L18	44	17 and (short \$3 test\$3 inspect\$3) adj2 (bar wir \$3 line circuit) and flexible adj2 circuit and (ic integrated adj circuit)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/25 15:59
L19	10	17 and (short \$3 test\$3 inspect\$3) adj2 (bar wir \$3 line circuit) and flexible adj2 circuit and (ic integrated adj circuit) and (test\$3 inspect \$3 bound\$3 short\$3) adj2 (pad terminal)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/25 16:00
L20	611	345/93	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/25 16:01
L21	2	20 and (short \$3 test\$3 inspect\$3) adj2 (bar wir \$3 line circuit) and flexible adj2 circuit and (ic integrated adj circuit) and (test\$3 inspect \$3 bound\$3 short\$3) adj2 (pad terminal)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/25 16:01

L22	19	8 and (short\$3 test\$3 inspect \$3) adj2 (bar wir\$3 line circuit) and flexible adj2 circuit and (ic integrated adj circuit) and (test\$3 inspect \$3 bound\$3 short\$3) adj2 (pad terminal)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/25 16:02
L23	8	10 and (short \$3 test\$3 inspect\$3) adj2 (bar wir \$3 line circuit) and flexible adj2 circuit and (ic integrated adj circuit) and (test\$3 inspect \$3 bound\$3 short\$3) adj2 (pad terminal)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/25 16:02
L24	6	12 and (short \$3 test\$3 inspect\$3) adj2 (bar wir \$3 line circuit) and flexible adj2 circuit and (ic integrated adj circuit) and (test\$3 inspect \$3 bound\$3 short\$3) adj2 (pad terminal)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/25 16:03

L25	10	14 and (short \$3 test\$3 inspect\$3) adj2 (bar wir \$3 line circuit) and flexible adj2 circuit and (ic integrated adj circuit) and (test\$3 inspect \$3 bound\$3 short\$3) adj2 (pad terminal)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/25 16:03
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